

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of:
Akiko F. Balchiunas

Atty. Docket No.: BUR920040137US1

Serial No.: 10/709,729

Group Art Unit: 2829

Filed: May 25, 2004

Examiner: Tang, Minh Nhut

For: INCREASE PRODUCTIVITY AT WAFER TEST USING PROBE RETEST DATA
ANALYSIS

AMENDMENT UNDER 37 C.F.R. §1.116

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This amendment is in response to the Office Action mailed January 23, 2007, setting a three-month statutory period for response. Therefore, this amendment is timely filed. Please amend the above-identified patent application as follows: